

TB2009 Analysis in Prague

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Whole report ~100 pages with many details now available on our wiki in direct link: http://aldebaran.hll.mpg.de/twiki/pub/DepfetInternal/TBResults2009PraguePage/201004_TB2009PrgAnal_Rel1.pdf or on wiki page:

http://aldebaran.hll.mpg.de/twiki/bin/view/DepfetInternal/TBResults2009PraguePage



DEPFET Beam Test 2009 - Prague Analysis Report

Contents

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Institute of Particle and Nuclear Physics, Faculty of Mathematics and Physics, Charles University in Prague	1 Introduction	3			
	2 Basic Beam Test 2009 Description	6			
	3 Analysis Outline				
Release #1 Last version: April 30, 2010	4 Lab Characterization	14			
	5 Beam Test Analysis Before Tracking	15			
	5.1 Raw data inspection - frame display	15			
	5.2 "Black" correction	17			
	5.3 "White" correction - pixel gain estimation	17			
	5.4 Hit reconstruction	17			
	5.5 DST production	18			
Internal report describing Prague analysis of the beam test 2009 at SPS CERN	6 Gain Correction	30			
	6.1 Introduction to Gains	30			
	6.2 Gain equalization	30			
	6.3 Results	32			
	7 Centre-of-Gravity Calculation	40			
	8 η Correction Results	42			
	9 Alignment and Tracking Analysis	46			

CO	NTENTS	2
10	(Mechanical) Stability Of Measurement	50
11	Large Scale Response (LSR) Correction	53
12	MC Simulations: Verification of the Analysis	56
13	Calculation of Detector Resolutions	61
14	Sub-Pixel Analysis from the Beam Test	63
15	Residuals And Resolution Final Results	76
16	Edge Scan	83
17	Bias Scan	91
18	Energy Scan	93
19	Alignment Scan	102
20	Conclusions	103

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Contents

- Description of analysis
- Beam test analysis before tracking
- Gains -> talk of Peter Kvasnička
- Mechanical stability of measurement
- Sub-pixel analysis from the beam test
- Residuals and resolution final results
- MC Simulations: verification of the analysis
- Edge scan
- Bias scan
- Alignment scan
- Energy scan
- Conclusion



Description of analysis





Description of analysis

Geometry of DEPFET TB, CERN - SPS, August 2009

Detector thickness: 0.45mm Si

Beam: 120 GeV/c hadrons: protons (67%), pions (29.4%), muons (about 1% of the pion flux), and few Kaons (about 3%) The maximum delta_P of the beam line is 1.5%, depends on collimator settings (ref. by Ilias Efthymiopoulos), information is not confirmed.

There was additional setting of particle energy: 40, 60 and 80 GeV/c electrons, unknown detail structure of beam.



* - on position 2 alternate next two modules as DUT:

Depfet12(the same S3B board): Waf 92, Chip J12, Type C3G L A, H3.0.01, 0.032x0.024mm Depfet7: Waf 90, Chip G11, Type COCG S E, H3.0.07, 0.024x0.024mm

Description of analysis

Scan test description	Acquired events	Hits	Η	its per pixe	<u>əl</u>
Whole dataset	7374599	110618985		6751.6	
H.3.0.16	380595	5708925		348.4	Γ
H.3.0.07	933668	14005020		854.7	Τ
H.3.0.04	1012110	15181650		926.6	
H.3.0.10	2074048	31110720		1898.8	
H.3.0.11	945658	14184870		865.7	Τ
H.3.0.12	1027314	15409710		940.5	Τ
H.3.0.06	1001206	15018090		916.6	/

Table 2.1: Characterization scans performed at MPI with the summaries as obtained from Prague analysis

Scan test description	Acquired events	Events per pixel
Whole beam test	4288627	261.7
Bias scan	507275	30.9
Banch Mark PLL24MHz2 33ms frame	33671	2.0
Alignment scan	806887	49.2
Long scan 1	384885	23.4
Edge scans	643922	39.3
Long scan 2	234046	14.2
Biasscan	500295	30.5
High frame occupancy scan	63210	3.8
Energy scans (all)	533629	32.5
e - 60 GeV (1)	16735	1.0
e - 60 GeV (2)	239877	14.6
e - 40 GeV	158254	9.6
e - 80 GeV	55553	3.3

Table 2.2: Beam test scans with the summaries as obtained from Prague analysis



Description of analysis

The main program on TB2009:

- Bias scans 100-200 V
- Edge scan (to study edge effects)
- Alignment scan: shift of detector #2 at the level of a few microns was performed
- Beam energy scan (to test for the effects of multiple scattering): 40, 60, 80, 100, 120 GeV/c – electrons and pions



Beam test analysis before tracking

Analysis of individual planes:

- 1. raw data inspection / frame display
- 2. "black" correction (pedestals, CMN, pixel noise)
- 3. "white" correction pixel gain estimation
- 4. hit reconstruction (pixel COG and η correction)
- 5. production of DST



Beam test analysis before tracking

(one special comment)

Stability of CMN correction over measurement time

The plots show CMN for 2 coordinates.

The first plot shows CMN correction for the first halfrows at a distance (y-axis) between 0 and 256 from the start readout row (data for the other half-rows are not shown).

The second plot shows CMN correction in the 64 columns of the sensor.

The horizontal axes show measurement time or event number and homogenity on x - direction confirm stable response over whole run.

Color scale is typically in range ±40 ADU or less.

There is first time to visualize this effect because we know position of start raw. There is no need to do any special analysis step base on this.





Mechanical stability of measurement



Upper plots horizontal axis shows LSR distribution in column or row, in vertical axis are sections of run (time or event distribution) and the color scale is in range $\pm 5 \,\mu$ m. The lower plot shows medians of LSR for each section and are corresponding with vertical axis of upper plot. The vertical scale is in range ±5 μ**m**.

Mechanical stability of measurement



After mechanical corrections.

Mechanical stability of measurement



After LSR and mechanical corrections.

Sub-pixel analysis from the beam test





COG + η – correction position calculations (give worst information)



Resolution





Distribution of values



Sub-pixel analysis from the beam test

		ax	is x	axis y		
Value	Module	Minimum	Maximum	Minimum	Maximum	
Residuals	2	1.4	1.6	1.2	1.5	
${ m in}\;\mu{ m m}$	3	1.5	2.4	1.4	1.85	
Resolutions	2	1.0	1.2	0.8	1.2	
${ m in}\;\mu{ m m}$	3	1.0	2.0	0.9	1.5	
	Module	Mini	mum	Maximum		
Cluster Charge	2	31	.80	3280		
in ADU	3	18	350	1900		
Seed	2	12	200	1900		
in ADU	3	9	00	1600		
Cluster Size	2	8	.0	9	.4	
	3	4	.8	6.2		

Table 14.1: Measured minima and maxima for residuals, resolution, cluster charge, seed and cluster size.

Residuals and resolution final results

$\begin{array}{c} \text{Residuals} \\ \text{in } \left[\mu \mathbf{m} \right] \end{array}$	$ \begin{array}{c} \text{Module 0} \\ \text{H.3.0.06} \\ \text{COCG L B} \\ 32\text{x}24 \ \mu\text{m} \end{array} $		Module 1 H.3.0.16 COCG L B 32x24 µm		Module 2 H.3.0.07 COCG V S 20x20 µm		Module 3 H.3.0.12 COCG L B 32x24 µm		Module 4 H.3.0.11 COCG L B 32x24 µm		Module 5 H.3.0.10 COCG L B 32x24 µm	
C/ 1	x	y	x	, y	x	y y	x	, y	x	y	x	y y
Truth residuals	2.49	2.28	1.60	1.38	1.54	1.42	1.98	1.61	2.06	1.61	3.24	2.86
MC Residuals	2.49	2.26	1.63	1.36	1.56	1.43	1.99	1.62	2.10	1.66	3.21	2.84
Diff Residuals	0.00	0.03	-0.03	0.02	-0.02	-0.01	-0.02	-0.01	-0.04	-0.05	0.03	0.02
NoTimeCor	1.68	1.55	1.09	0.92	1.66	1.13	1.69	1.30	1.54	1.18	2.37	3.23
Dif $2x2$ (LSR)	0.10	0.04	0.07	0.04	0.23	0.10	0.05	0.05	0.09	0.13	0.05	0.04
Dif 3x3 (LSR)	0.05	0.02	0.04	0.03	0.15	0.09	0.04	0.04	0.08	0.13	0.04	0.03
Best $2x2 + det #2 3x3$	2.49	2.28	1.60	1.38	1.54	1.42	1.98	1.61	2.06	1.61	3.24	2.86
OnePixelEta	2.50	2.33	1.61	1.42	1.68	1.50	1.98	1.64	2.06	1.64	3.23	2.91
Diff OnePixel	-0.01	0.05	0.00	0.03	0.00	0.03	0.00	0.03	0.00	0.03	-0.01	0.05

Table 15.1: Residuals in x and y axes from Prague analysis for different cases of corrections or analysis ways, run 2144. Error of residuals can be estimated to 0.1 μ m. 2x2 means COG calculation was done from highest 2x2 pixels arround seed, 3x3 means all neghbouring pixels used for COG position calculation.



Typical residual 2D plots for all detectors, counts in color scale are in the logarithmic scale. Axes x and y are in range $\pm 20 \ \mu m$.

MC Simulations: Verification of the Analysis





Edge scan



- 1. One module affects average residuals and resolutions on all others
- 2. Self-effect is about extra 0.04 µm
- 3. Other modules worsen by about extra 0.05 - 0.15 µm (affect alignment and tracking)
- Affects average cluster charge and seed 4.
- 5. Small influence on the cluster size

Module H3.0.07 - edge effect, distance between track and hit vs position on axis

0.03

-0.03

0.03

0.02

0.01

-0.03

Before LSR correction





in axis x

in axis)



h2 ResProd 5

-10 V

in axis y



Peter Kodyš, DEPFET, Ringberg, May 2010

h2_ResPred_

0.04

-0.02

-0.03

0.03

0.02

0.01

-0.03

0.05 0.04 0.03 0.02 0.01 -0.01 -0.02 -0.02

h2 ResPred

h2 ResProd

0.04

-0.01

-0.02

Edg

Edge

h2_ResPred_4 0.05 0.04



Edge scan

Module H3.0.07 - edge effect, hit maps and cluster charge vs position on axis





Bias scan



Possible problem is that there is no clear visible saturation on cluster charge over voltage ~160 V.



Alignment scan

Study of how the movement of a detector along one axis and corresponding changes in alignment shift. The comparison shows that alignment reproduces small movements of the detector with the precision of $0.14 \pm 1.23 \mu m$. Typical (RMS) variations of alignment shifts are in the range $0.33 - 1.10 \mu m$.

The corresponding variation in residuals and resolutions are in the range 0.02 - 0.06 μ m, which is well below their typical variation (0.1 μ m).

- Alignment scan is mechanically at the edge of abilities of the positioning tables.
- Additional mechanical forces come from thick cables and have long relaxation time
- The moves by several microns indeed have low repeatability, and the response of the positioning tables at such moves is not well defined.
- The mechanical setup is known to displace on micron scale during long experiments



Beam Test

Energy scan

pions – good agreement between beam test data and simulations.

electrons – discrepancy between data and simulations on the level of 1.3 - 1.8 µm higher value for residuals from beam test.

For electrons: We cannot reproduce in simulations the scatter observed in TB data!

Possible explanations:

- 1. Too low rate of accepted tracks per hour which gives come problems in compensation of mechanical instabilities.
- 2. Contamination of beam with an additional fraction of particles with lower energy and different types (This message is coming from consultations), still under discussion...
- 3. Unexpected shift of energy to lower values about 10-15 GeV/c compared to the nominal energy

Comparison with other analyses would be vital.

At the lower energies of electrons a smaller rate of tracks per hour gives some problems in compensation of mechanical instabilities. Results are highly sensitive to this correction - changes on the level of 2 µm are possible

Very special fit only for top hat for 100 GeV/c electrons



(yellow), fit is not good for TB

electrons

Simulation



Conclusion

- Analysis of DEPFET TB2009 in Prague is almost complete.
- Final results obtained are presented: individual detector resolutions (and corresponding residuals), resolution vs. sub-pixel position, edge scan, resolution vs. bias, alignment properties and energy scan.
- The analysis shows consistent behavior of tested DEPFET modules over the whole course of the beam test and some new mysteries: energy scan of electrons, from where it comes?
- Main goal now is tune standard analysis based on Mokka/Marlins ILC framework

	Module 0		Module 1		Module 2		Module 3		Module 4		Module 5	
	H.3.0.06		H.3.0.16		H.3.0.07		H.3.0.12		H.3.0.11		H.3.0.10	
Resolution	COCG L B C		COCO	COCG L B		COCG V S		COCG L B		COCG L B		GLΒ
in $[\mu m]$	$32x24 \ \mu m$		$32x24 \ \mu m$		$20\mathrm{x}20~\mu\mathrm{m}$		$32x24 \ \mu m$		$32x24 \ \mu m$		$32x24 \ \mu m$	
	x	У	x	У	x	У	x	У	x	У	x	У
Truth residuals	2.49	2.28	1.60	1.38	1.54	1.42	1.98	1.61	2.06	1.61	3.24	2.86
Truth resolutions	1.65	1.45	1.15	0.90	1.10	1.00	1.60	1.20	1.65	1.20	2.00	1.80

Table 20.1: Table of final residuals and resolutions in x and y axes from Prague analysis. Error of residuals and resolutions can be estimated to 0.1 μ m

Whole report ~100 pages with many details now available on our wiki in direct link: http://aldebaran.hll.mpg.de/twiki/pub/DepfetInternal/TBResults2009PraguePage/201004_TB2009PrgAnal_Rel1.pdf or on wiki page:

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